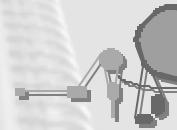


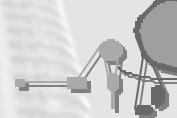
Ion Beam Induced Desorption Yield Measurements at GSI



ICFA Workshop, December 9-12, 2003

The 13th ICFA Beam Dynamics Mini-Workshop
Beam Induced Pressure Rise in Rings
Brookhaven National Laboratory, Upton, NY
December 9 - 12, 2003

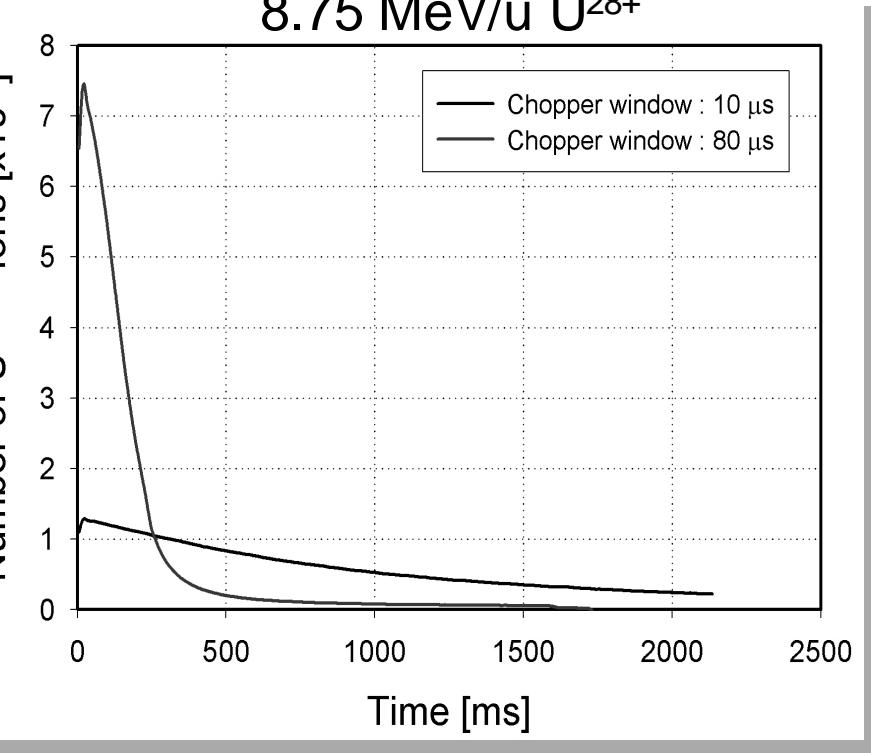
Dynamic Vacuum and Beam Lifetime



ICFA Workshop, December 9-12, 2001

P. Spiller, December 2001

8.75 MeV/u U^{28+}



Desorption processes degenerate the residual gas pressure.

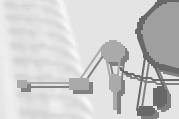
Initiated by:

- Systematic beam losses on acceptance limiting devices (septa)
- Stripped beam ions
- Ionized and accelerated residual gas

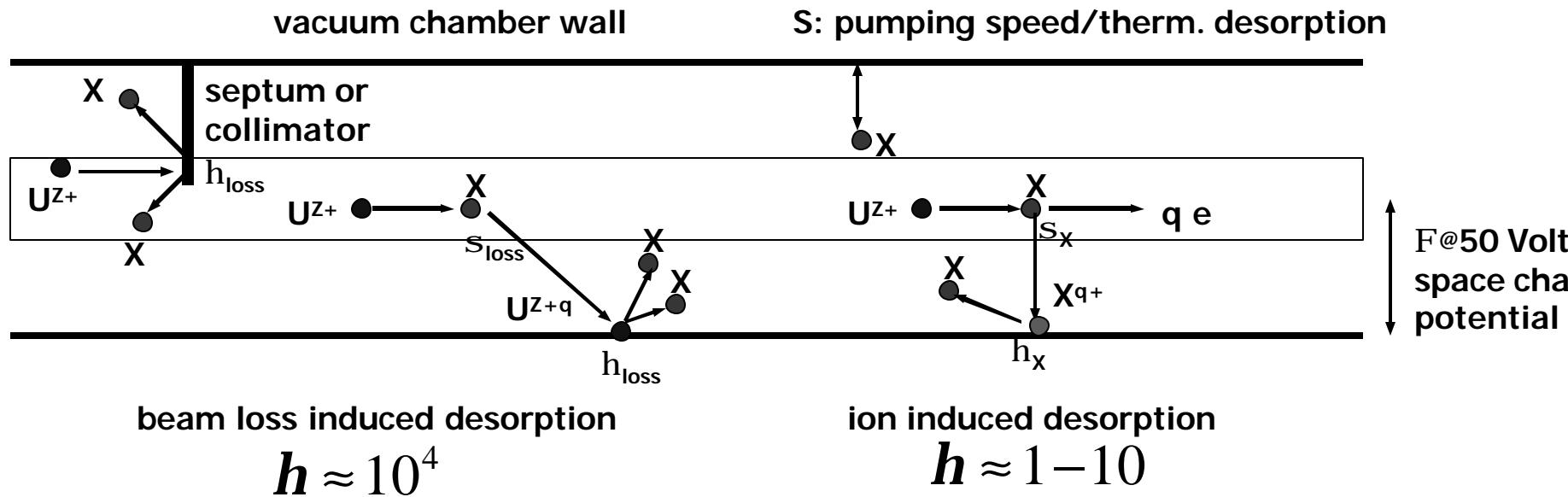
Beam losses increase with number of injected ions

(shorter beam life time due to stronger pressure bumps)

Desorption Processes in SIS18



ICFA Workshop, December 9-12, 2008

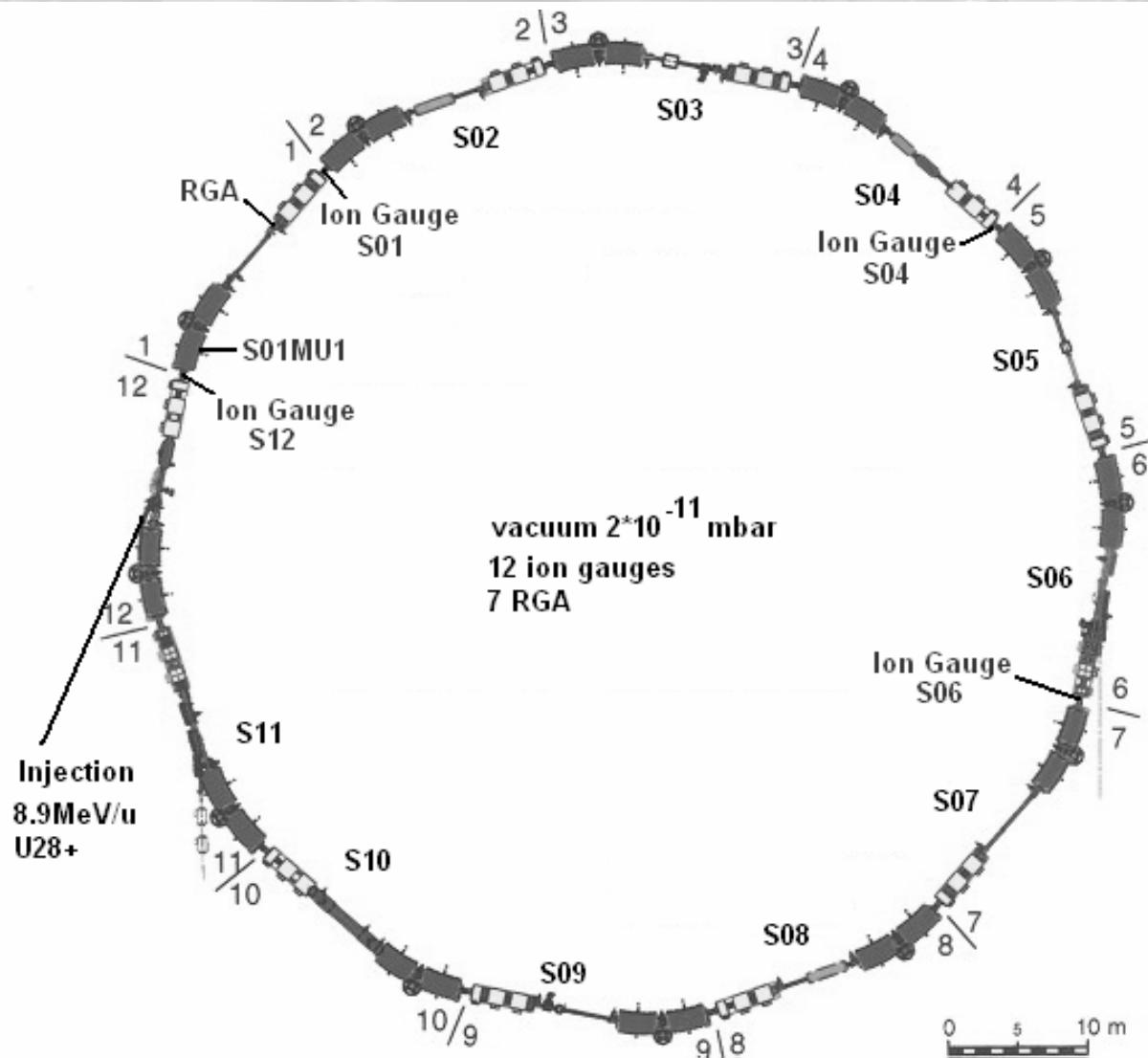


desorption yield η :

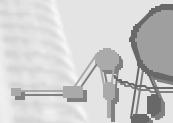
$$h = \frac{\text{emitted molecules}}{\text{incident ion}}$$

Measurements @ SIS18

ICFA Workshop, December 9-12, 2008

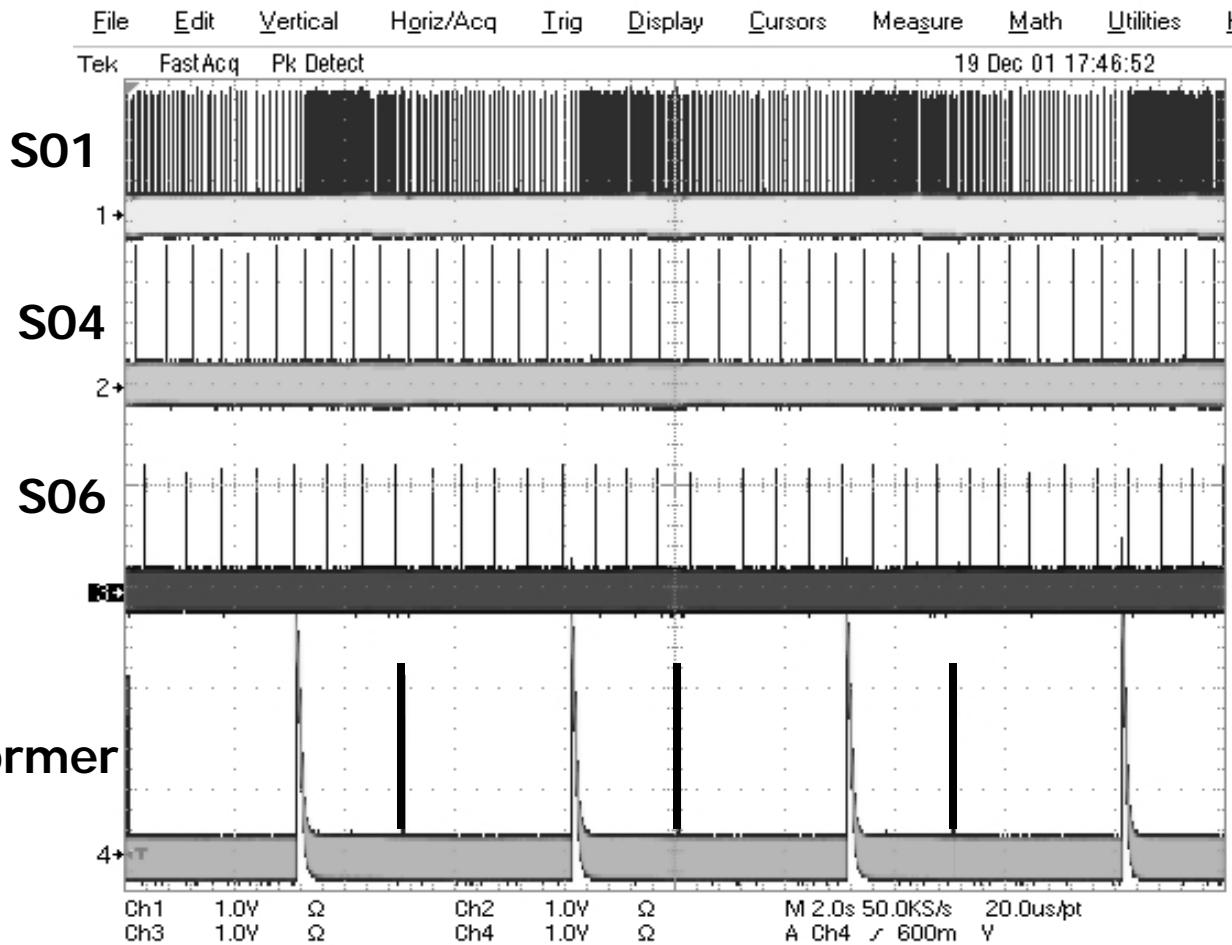


Fast Pressure Measurements in SIS18



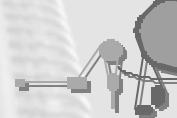
ICFA Workshop, December 9-12, 2001

First fast pressure measurements and prove of desorption processes in SIS18 in October 2001



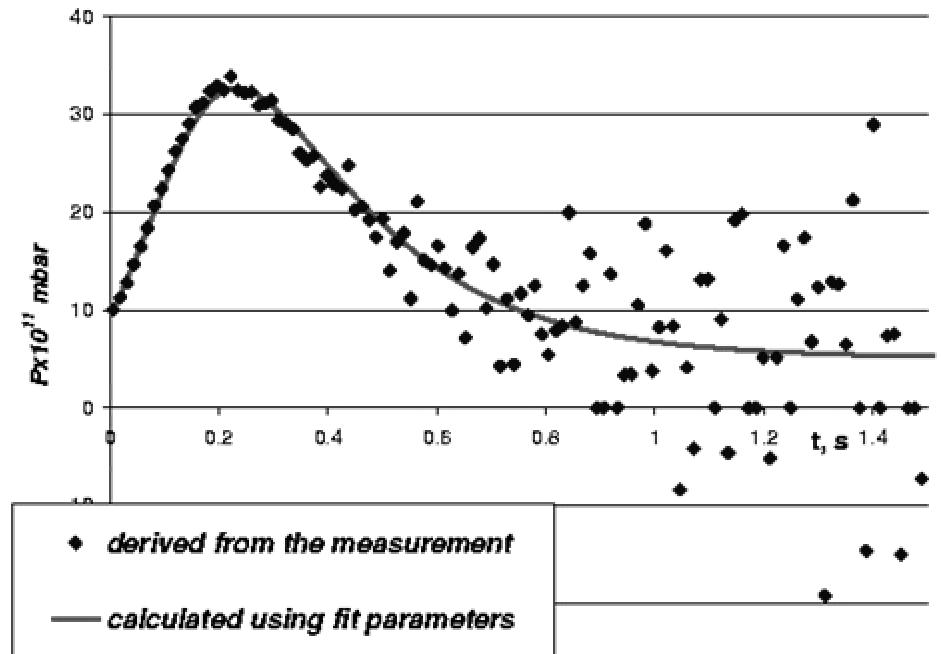
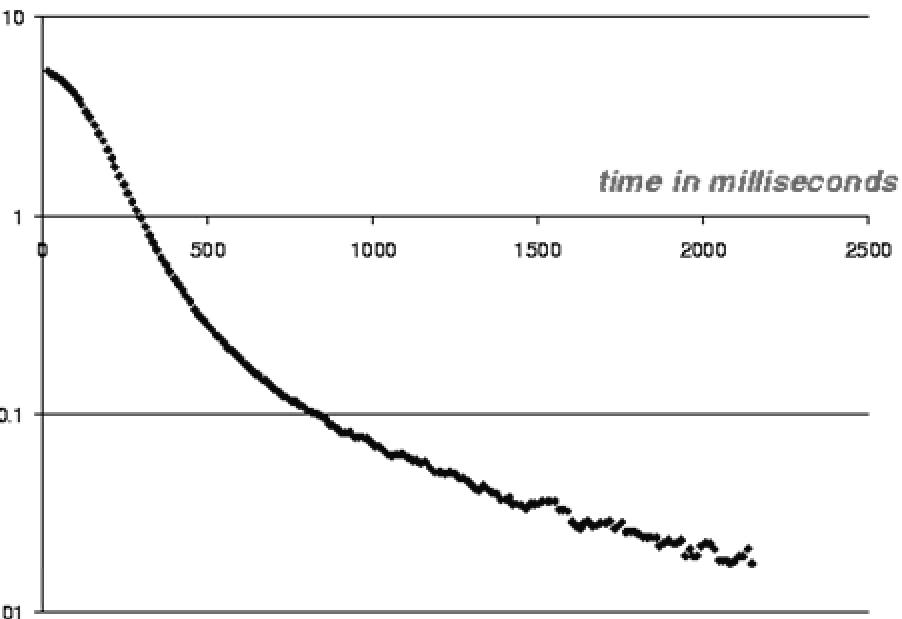
8.9 MeV/u U²⁸⁺

Vacuum Pressure Instability in SIS18



ICFA Workshop, December 9-12, 2003

U^{28+} ion beam lifetime @ 8.9 MeV/u

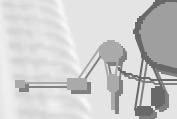


$$\frac{d}{dt} \ln\left(\frac{I}{I_0}\right) = -\frac{SLn}{T} l P = t_{life}$$

$$\frac{dP}{dt} = -\frac{S}{V}(P - P_e) + \frac{shL}{VeZ} IP$$

average pressure, I beam current, S pumping speed, h desorption yield, s charge exchange cross section.
(E. Mustafin et al., NIM A510, 199 (2003))

Fit Results for Lifetime Measurements of U²⁸⁺



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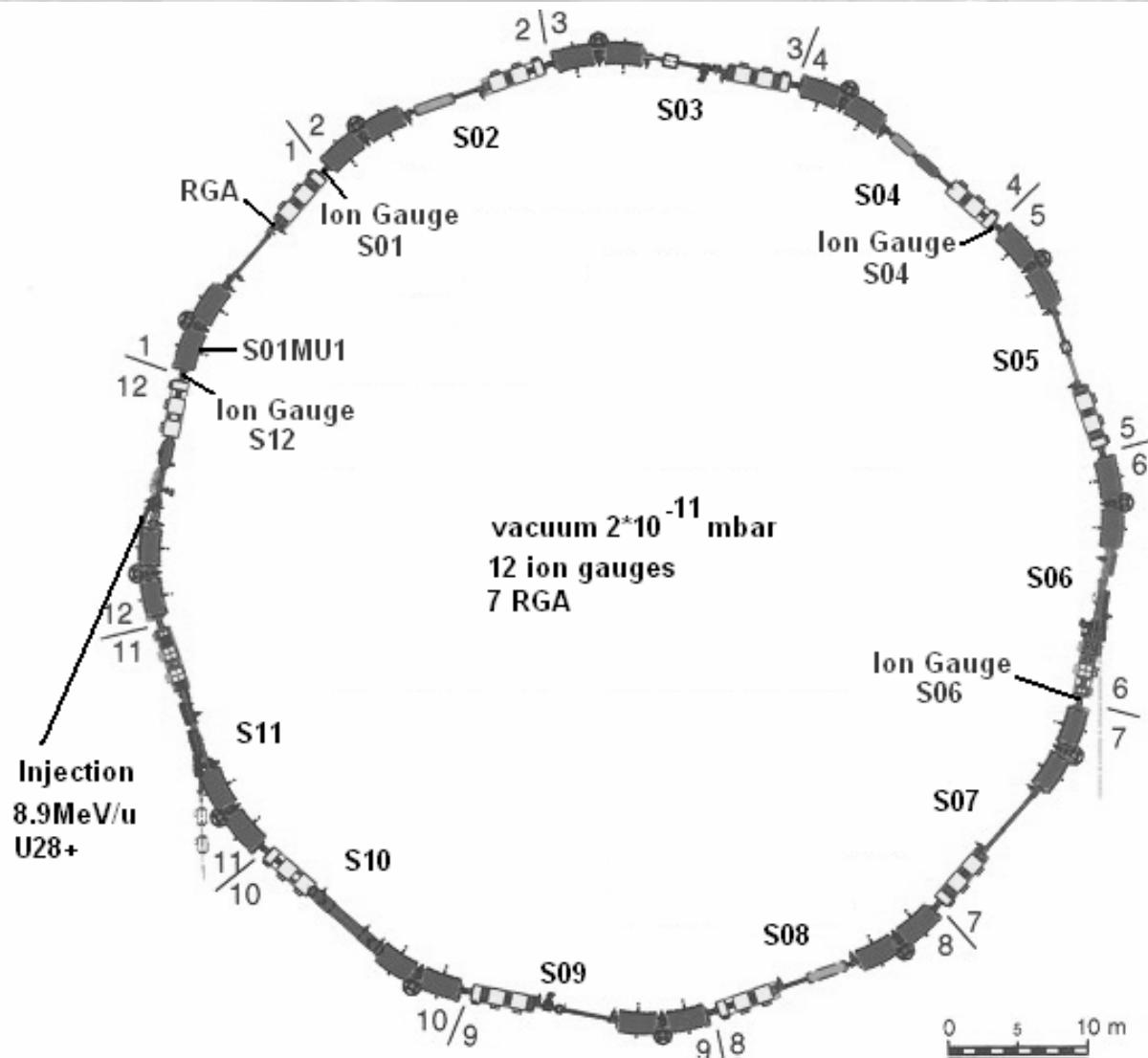
E. Mustafin et al., NIM A510, 199 (2003)

injected ion current [mA]	pumping speed [l/s per pump station]	σ charge exchange cross section [10^{-20} m^2]	desorption yield η	initial pressure [10^{-11} mbar]
1.08	160	1.1	20000	6.0
1.40	120	0.8	27000	14
1.97	160	1.3	16000	6.5
5.36	150	2.1	11000	10

1mA corresponds to 10^9 ions

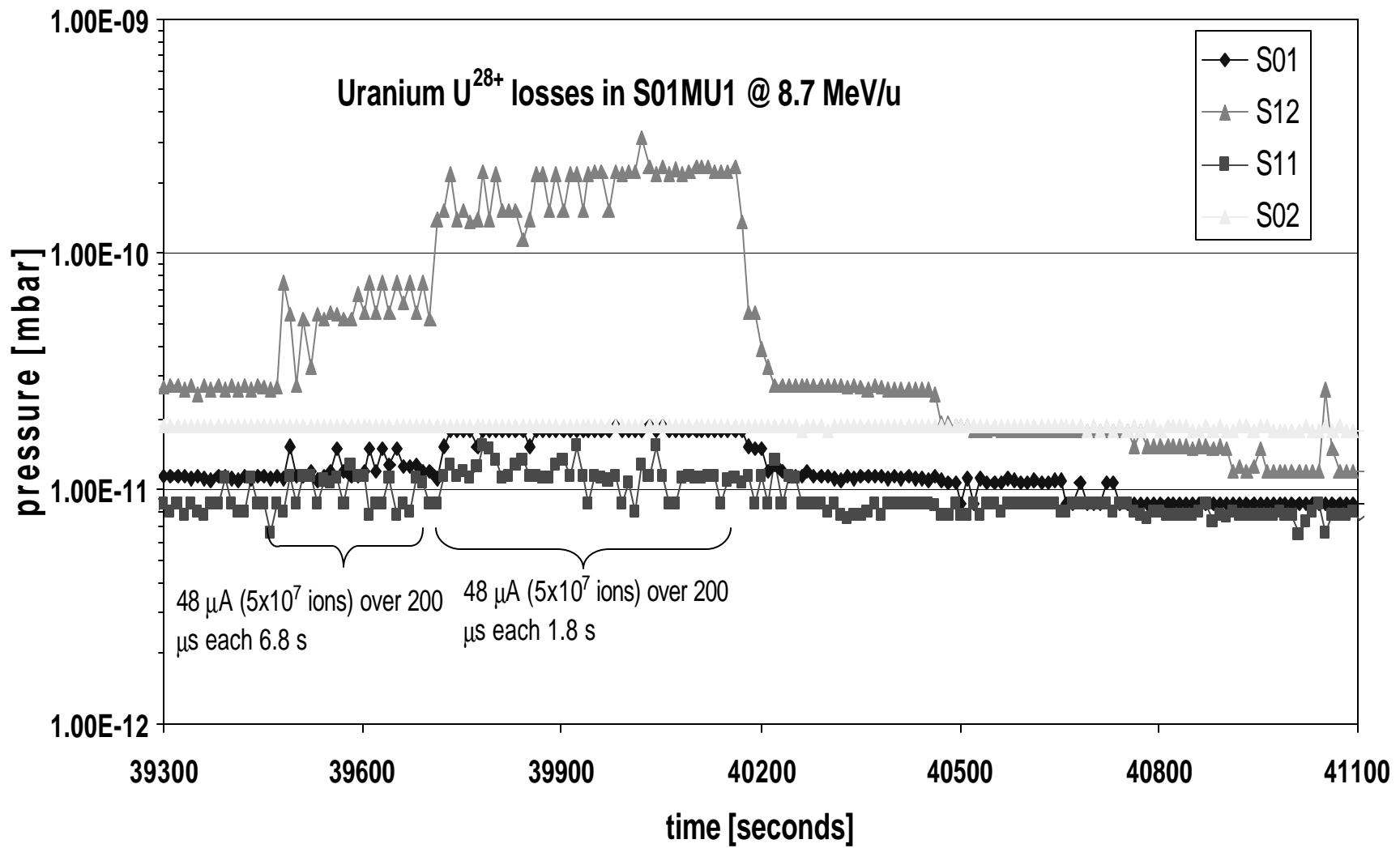
Measurements @ SIS18

ICFA Workshop, December 9-12, 2008



Pressure Rise During Localized Beam Loss

ICFA Workshop, December 9-12, 2002

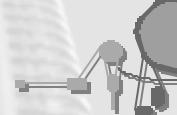


Weinrich et al., GSI Internal Report (2002)

Andreas Krämer - GSI Darmstadt

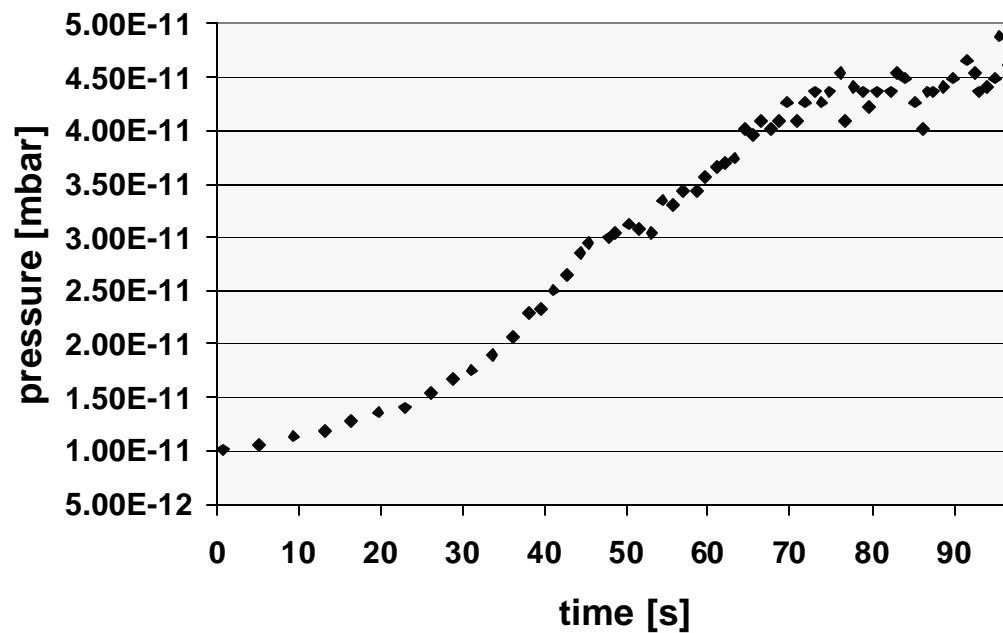
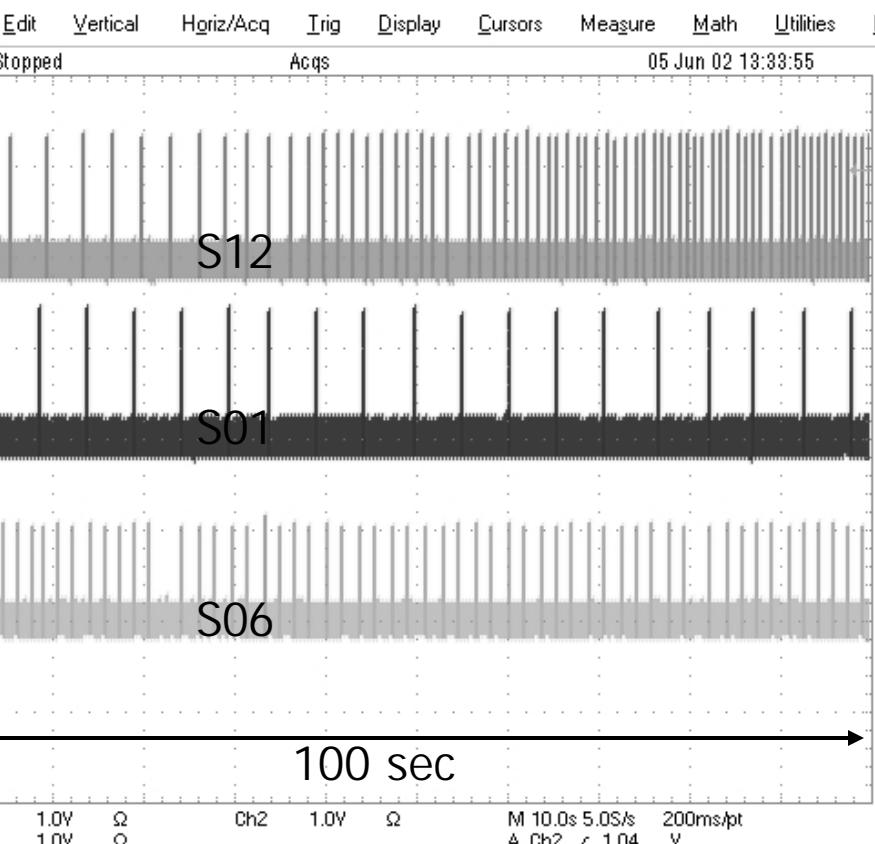


Fast Pressure Measurements



ICFA Workshop, December 9-12, 2002

Continuous injection of 8.7 MeV/u $5 \cdot 10^7$ U²⁸⁺ ions every 1.8 sec



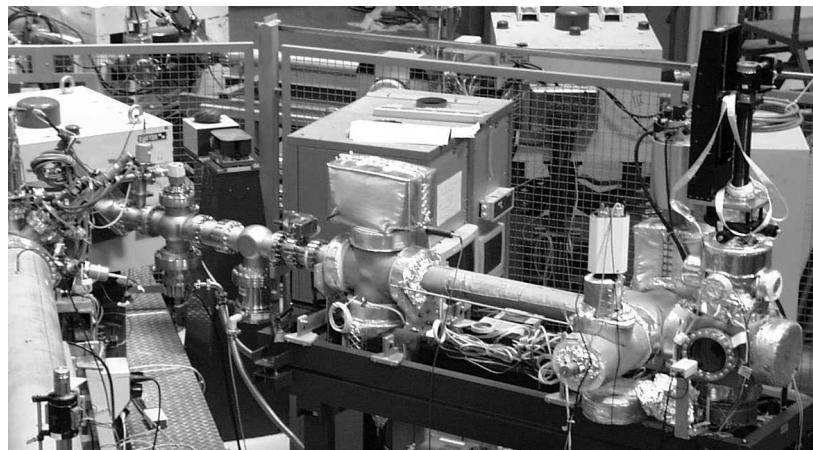
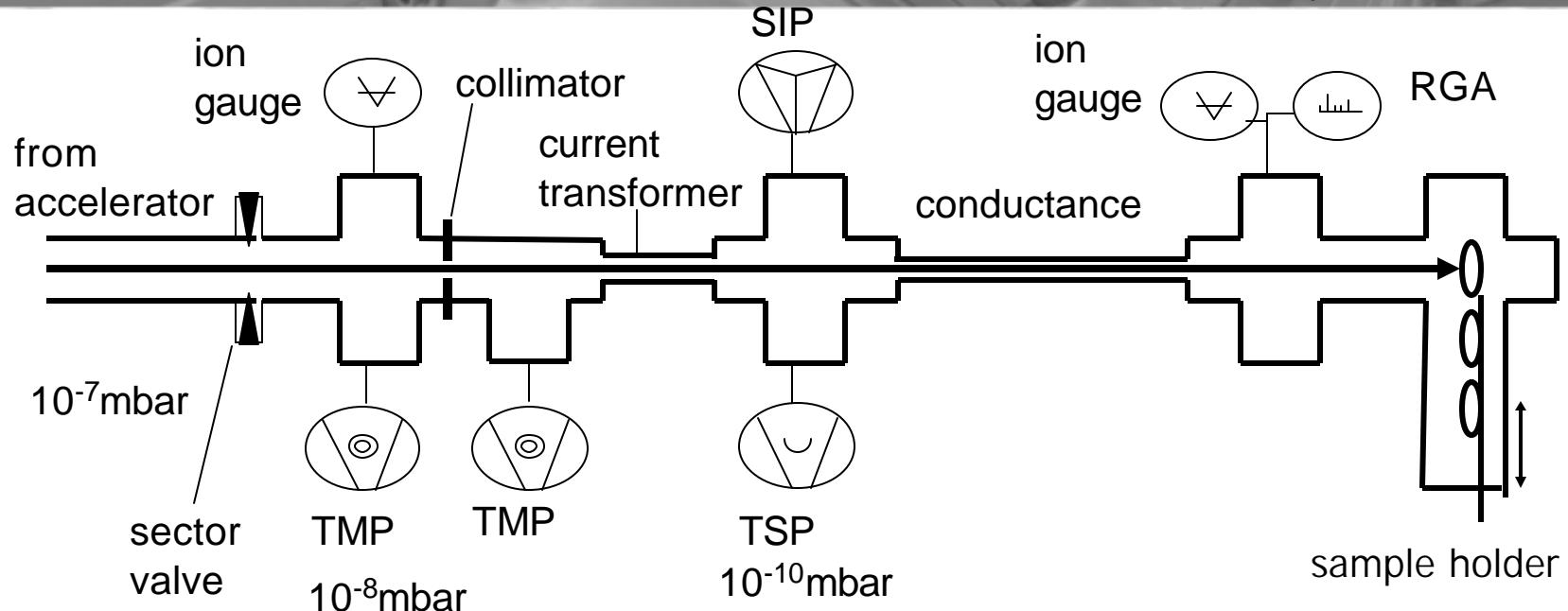
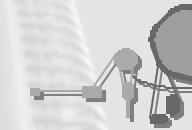
$$\eta \approx 5200$$

U. Weinrich et al., GSI Internal Report (2002)

Andreas Krämer - GSI Darmstadt

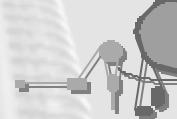
Experimental Setup for Ion Beam Induced Desorption Yield Measurements

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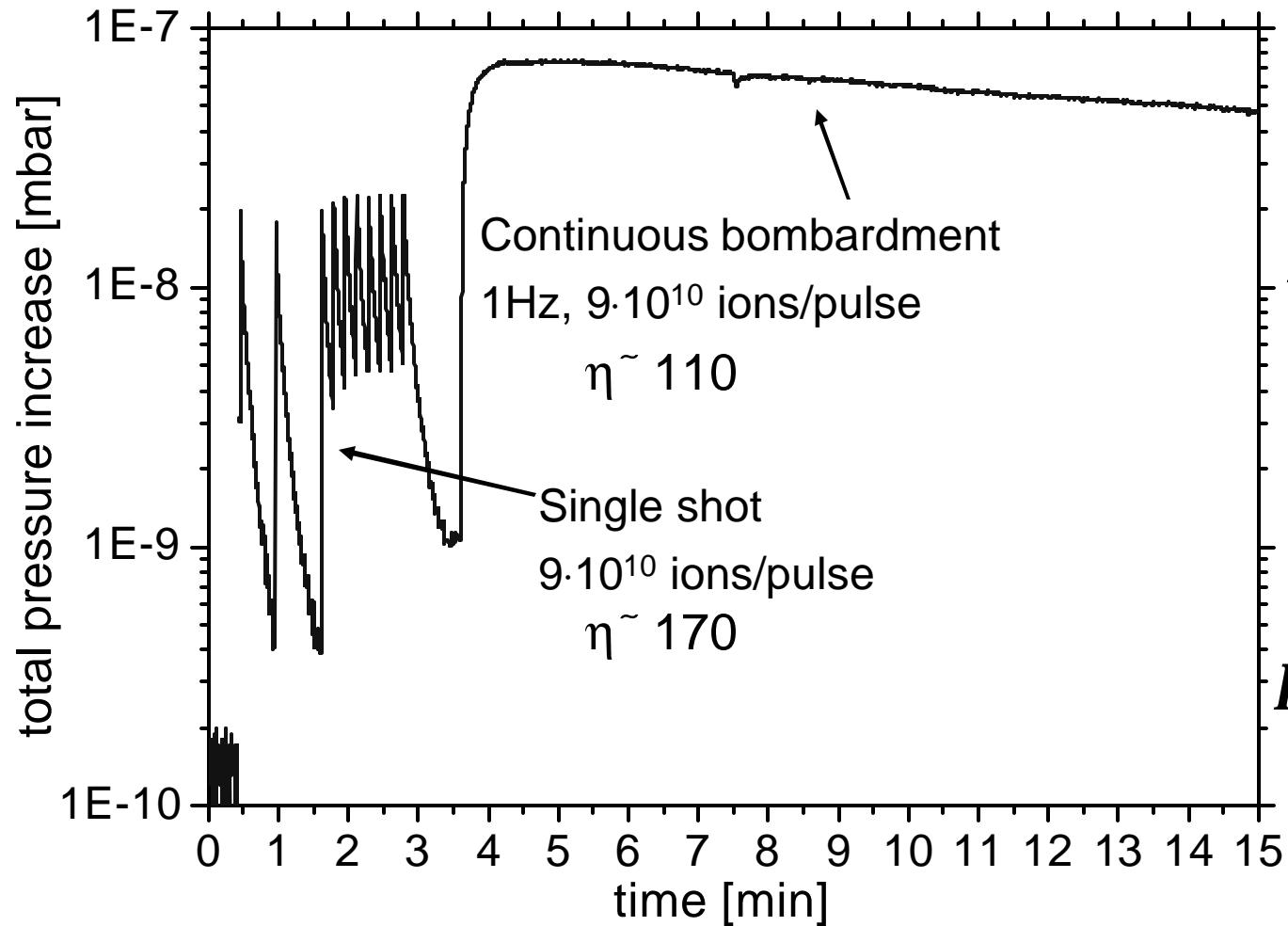
Experiments by:
M. Bender (GSI)
H. Kollmus (GSI)
A. Krämer (GSI)

Total Pressure Increase due to Desorption



ICFA Workshop, December 9-12, 2008

1.4 MeV/u C²⁺ \Rightarrow Al, perpendicular incidence



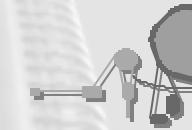
Single shot

$$h_{eff} = \frac{\Delta p \times V}{N_{ion} \times k_B \times T}$$

Continuous
bombardment

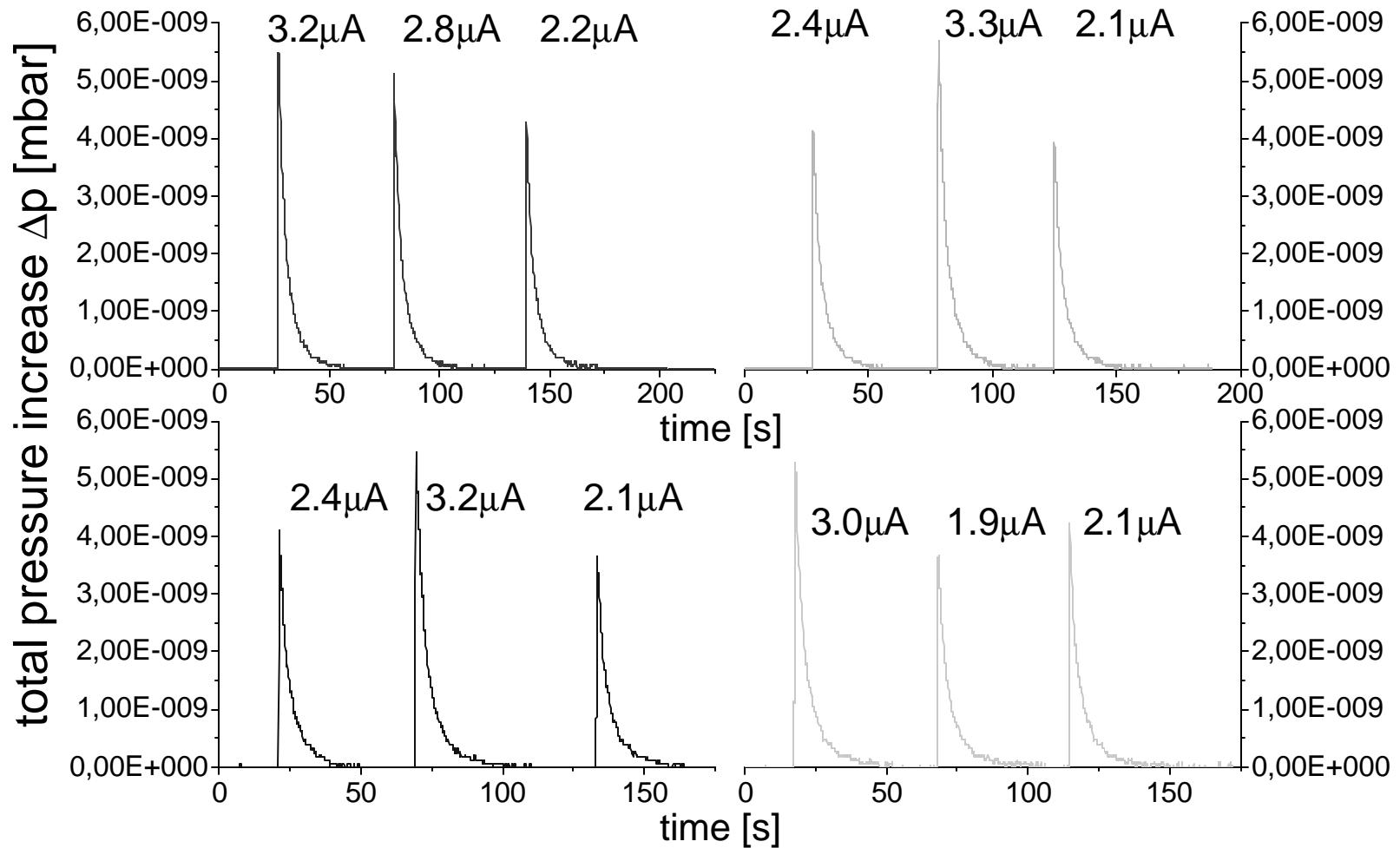
$$h_{eff} = \frac{\Delta p \times S}{\dot{N}_{ion} \times k_B \times T}$$

Total Pressure Increase due to Ion Beam Induced Desorption

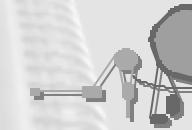


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1.4MeV/u $1.8\text{-}3.1 \cdot 10^9$ (1.9-3.3mA, 4ms) Pb²⁷⁺ P stainless steel 304

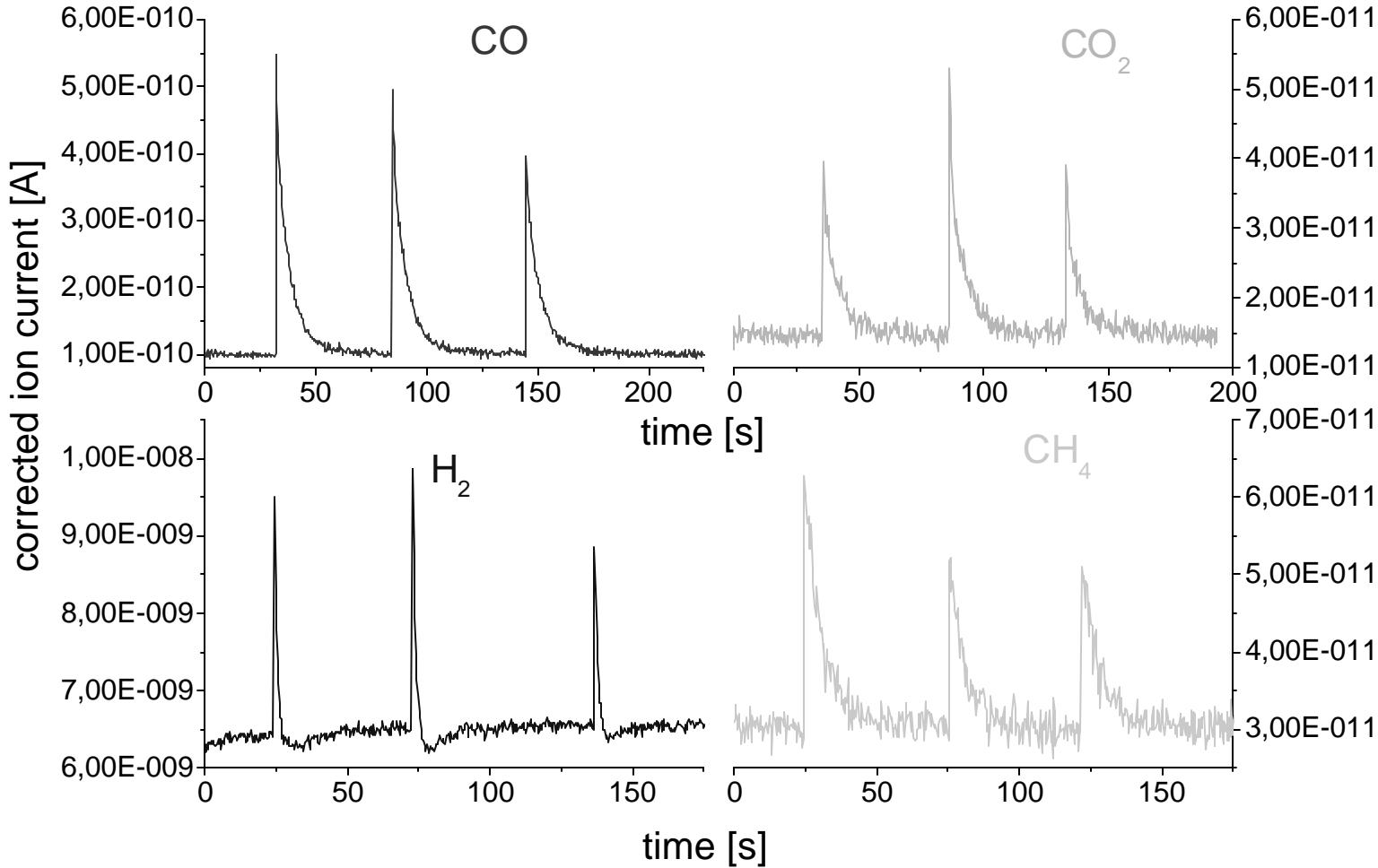


Partial Pressure Increase due to Ion Beam Induced Desorption



ICFA Workshop, December 9-12, 2008

1.4MeV/u 1.8-3.1·10⁹ Pb²⁷⁺ P stainless steel 304

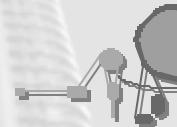


The measured ion current was corrected for the ionization probabilities of the different gases:

H₂: x2.3
CO: x0.95
CO₂: x0.71
CH₄: x0.625

P Desorption dominated by H₂ (87%) and CO (11%)

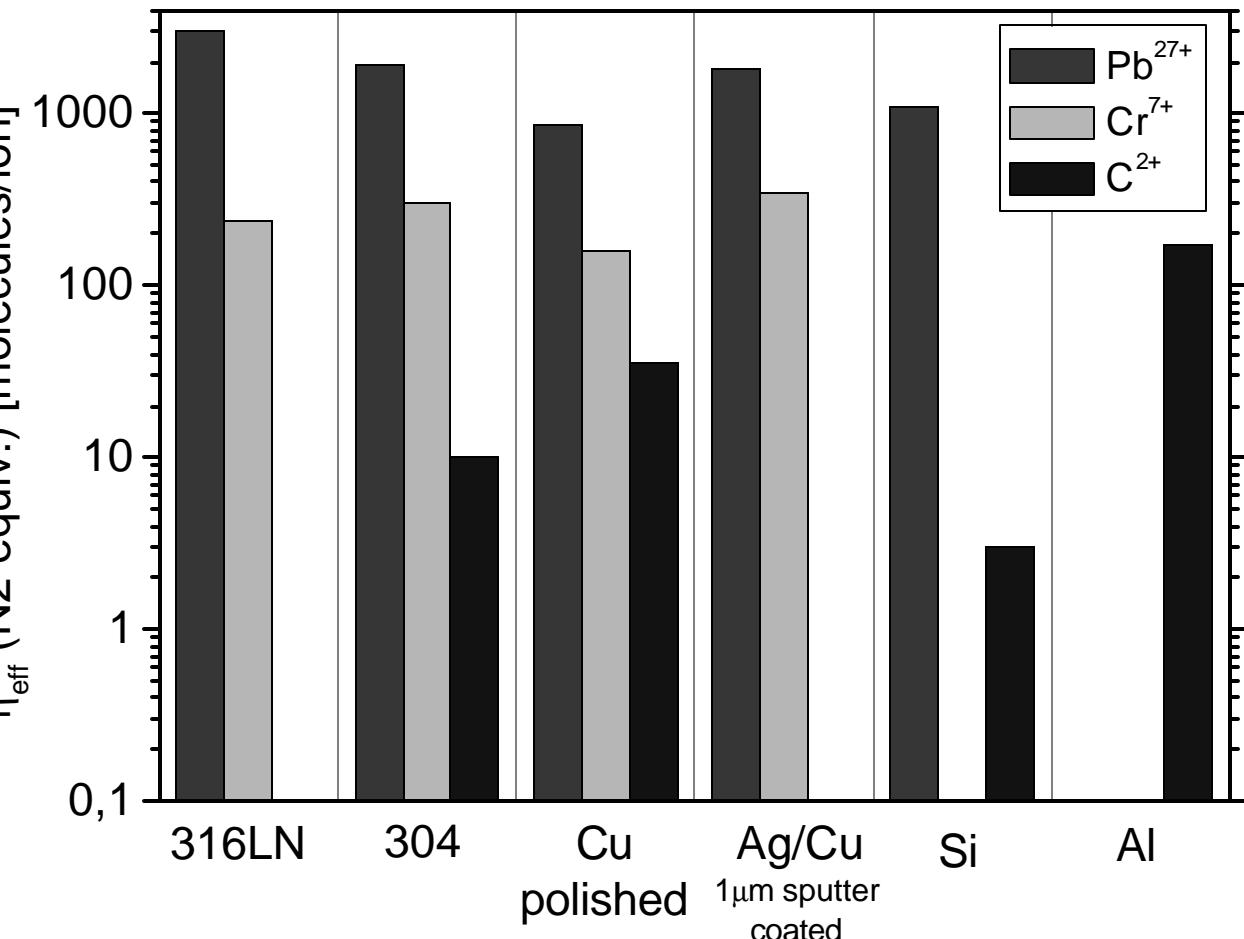
Single Shot Results of Desorption Yield Measurements at GSI



ICFA Workshop, December 9-12, 2008

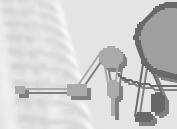
[M. Bender, H. Kollmus, A. Krämer (GSI UHV group)]

Energy: 1.4 MeV/u, Intensities: 10^9 – 10^{11} ions per pulse, perpendicular incidence

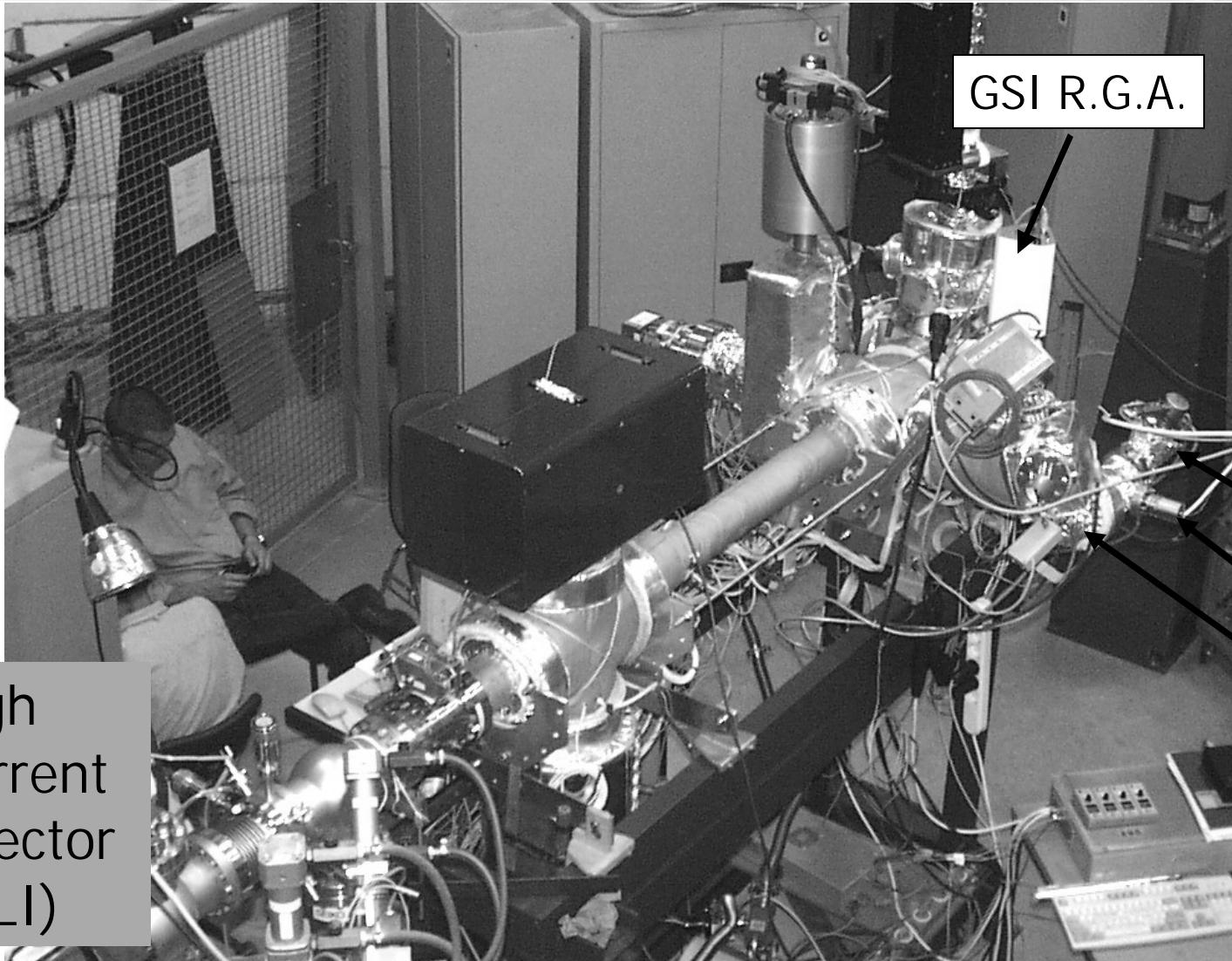


The calculated desorption yields are not corrected for the "real" gas composition, which is H_2 dominated. Therefore the desorption yields are underestimated by a factor of about 2.

Experimental Set-Up with additional CERN hardware



ICFA Workshop, December 9-12, 200



1.4MeV/u Zn¹⁰⁺

Experiment by:
E. Mahner (CERN)
M. Bender (GSI)
H. Kollmus (GSI)
A. Krämer (GSI)

CERN B.A.G.
GSI gauge
CERN R.G.A.

high
current
injector
(ILI)

Latest Experiment with Zn¹⁰⁺ at 1.4MeV/u

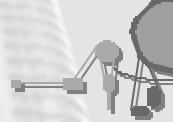
CERN Samples by Edgar Mahner



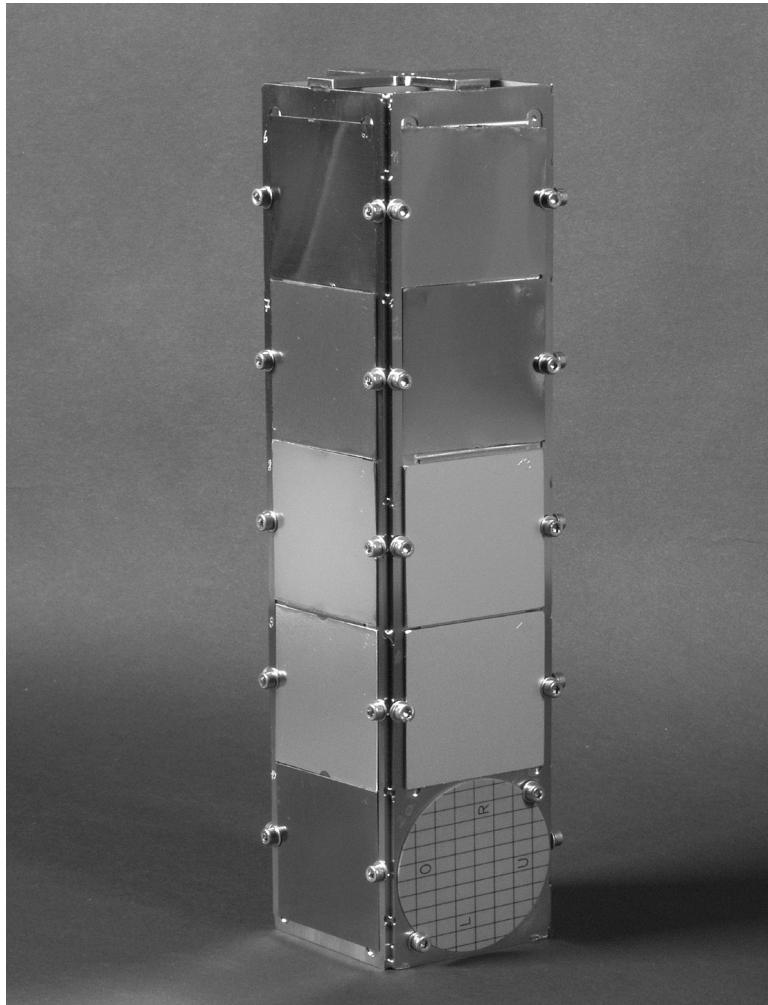
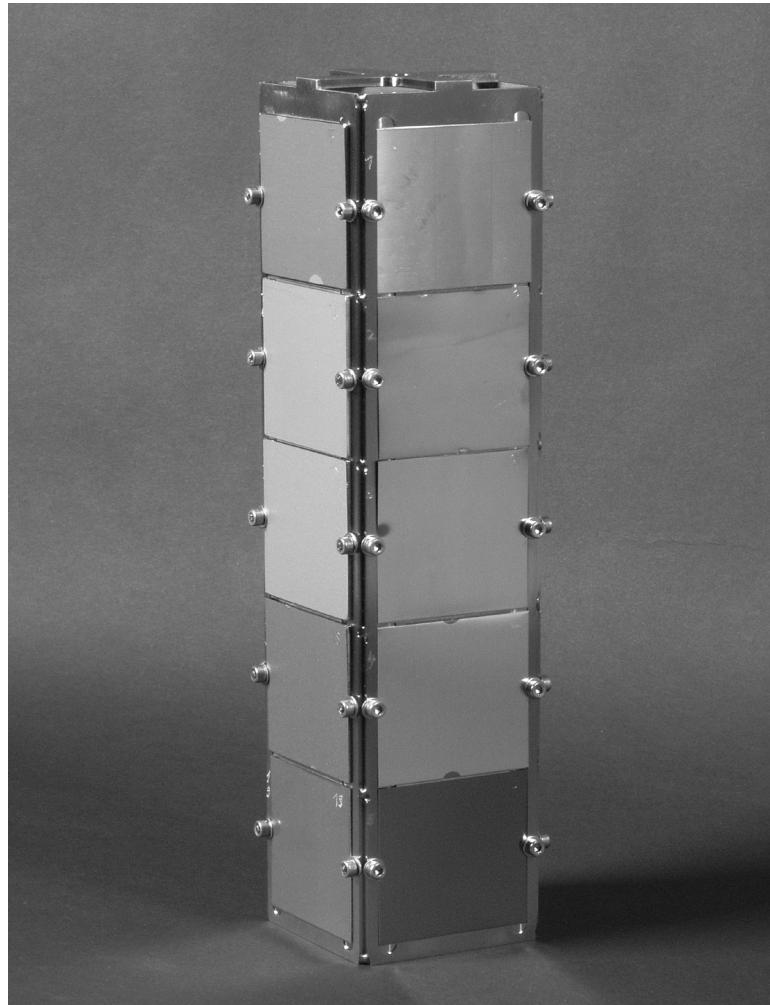
ICFA Workshop, December 9-12, 2008

Substrate	Dimensions [mm ³]	Temper, cleaning, vacuum firing	Sample #	Sputter coatings CERN	Final thickness
⁴¹ Nb (Nb)	50×50×0.25	annealed, degreasing	1 2	- Au (1.5 µm)	- (2.4 mm)
² Mo (Molybdän)	50×50×0.25	annealed, degreasing	3 4	- Ag (1.5 µm)	- (1.5 mm)
⁷³ Ta (Tantal)	50×50×0.25	annealed, degreasing	5 6	- Pd (1.5 µm)	- (0.3 mm)
⁷⁴ W (Wolfram)	50×50×0.20	as rolled, degreasing	7 8 9 10	- Au (1.5 µm) Ag (1.5 µm) Pd (1.5 µm)	- (2.4 mm) (1.5 mm) (0.3 mm)
⁷⁵ Re (Rhenium)	50×50×0.125	annealed, degreasing	11 12	- TiZrV (1.5 µm)	- (1.5 mm)
316 LN	50×50×1.5	as received, degreasing	13	-	-
316 LN	50×50×1.5	as received, degreasing, 950°C vacuum firing	14	-	-
316 LN	50×50×1.5	as received, degreasing, 950°C vacuum firing	15	TiZrV (1.5 µm)	(1.5 mm)
304 L	50×50×1.5	as received, degreasing	16	-	-
304 L	50×50×1.5	as received, degreasing, 950°C vacuum firing	17	-	-
304 L	50×50×1.5	as received, degreasing, 950°C vacuum firing	18	TiZrV (1.5 µm)	(1.5 mm)
1.4301 GSI	50×50×2	standard UHV cleaning	19	-	-

Target Holder with CERN Samples



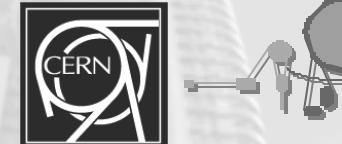
ICFA Workshop, December 9-12, 2008



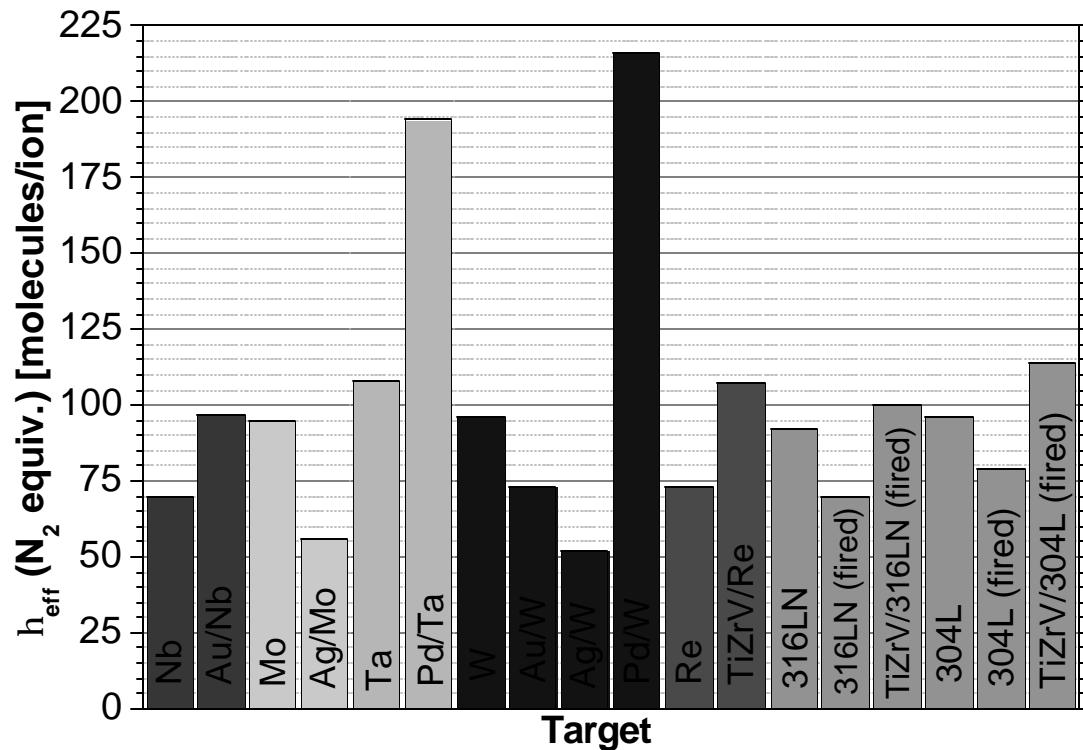
[pictures by G. Otto (GSI)]

Andreas Krämer - GSI Darmstadt

Desorption Yields calculated out of Single Shot Experiments



ICFA Workshop, December 9-12, 2008



1.4MeV/u Zn¹⁰⁺

Desorption yields are calculated with:

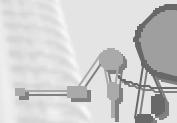
$$h = \frac{\Delta p \times S}{N \times k_B \times T}$$

assuming $S=5.52\text{ l/s}$
(N_2 equivalent)

Δp was measured with an extractor ion gauge.

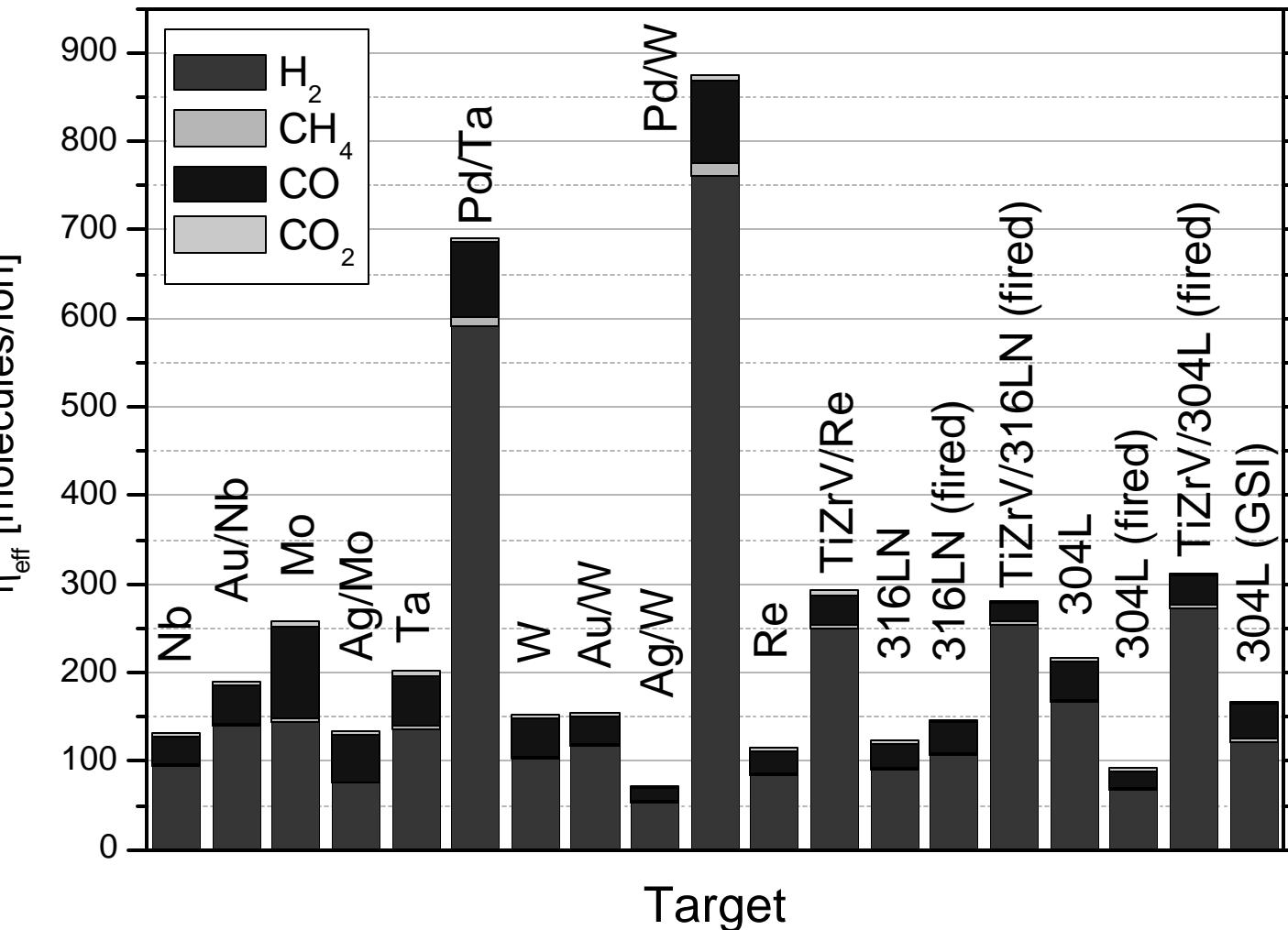
- No influence of the high melting temperatures of Nb, Mo, Ta, W, Re in comparison to 316LN and 304L
- η of coatings independent of thickness and bulk material

Desorption Yields Calculated from Scrubbing Plots by E. Mahner (CERN)



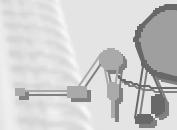
ICFA Workshop, December 9-12, 200

1.4MeV/u Zn¹⁰⁺



Mainly desorbed gases are H_2 and CO .

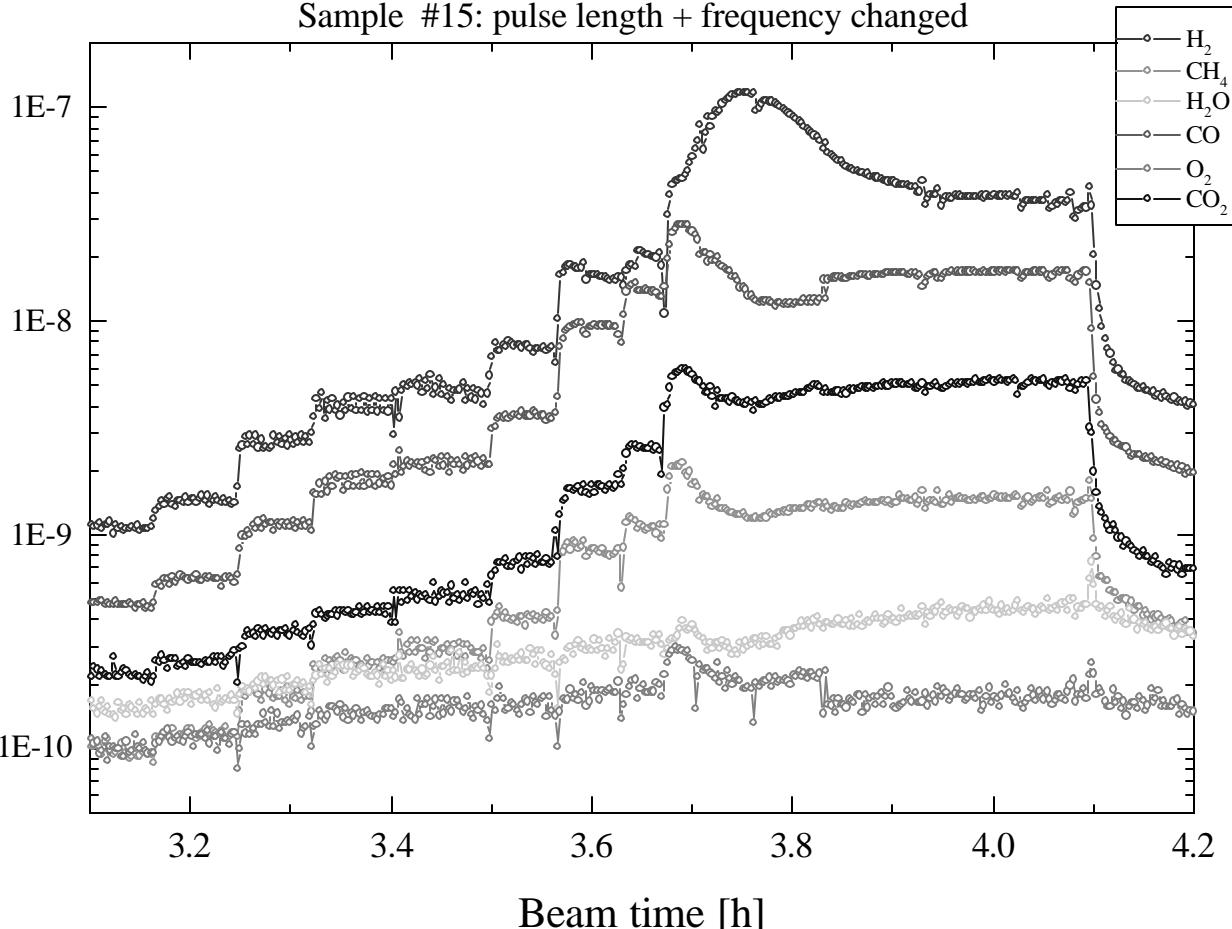
Pulse Length and Frequency Dependence of Partial Pressures



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1.4 MeV/u $Zn^{10+} \Rightarrow TiZrV/316LN$ (fired)

Sample #15: pulse length + frequency changed



Rate [Hz]	Pulse length [ms]
1	0.49
1	2
1	4
1	5.5
2	5.5
6.25	5.5
10	5.5
25	5.5

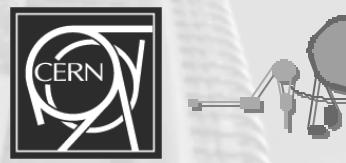
Intensity dependence of η :
• linear?
• new effects at high intensities?

by E. Mahner (CERN)

Andreas Krämer - GSI Darmstadt



Pulse Length and Frequency Dependence of Partial Pressures

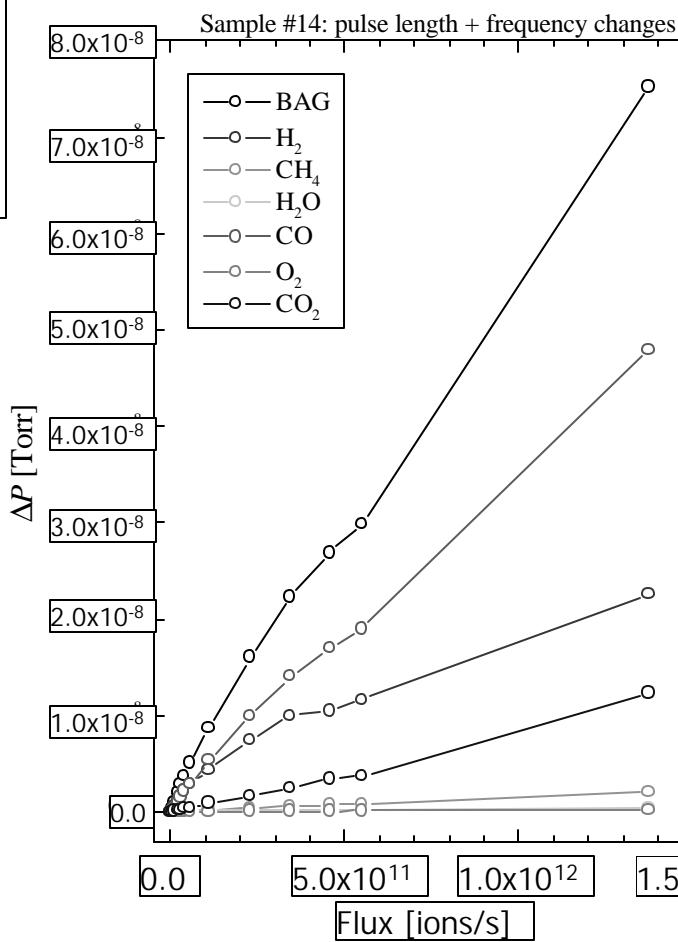
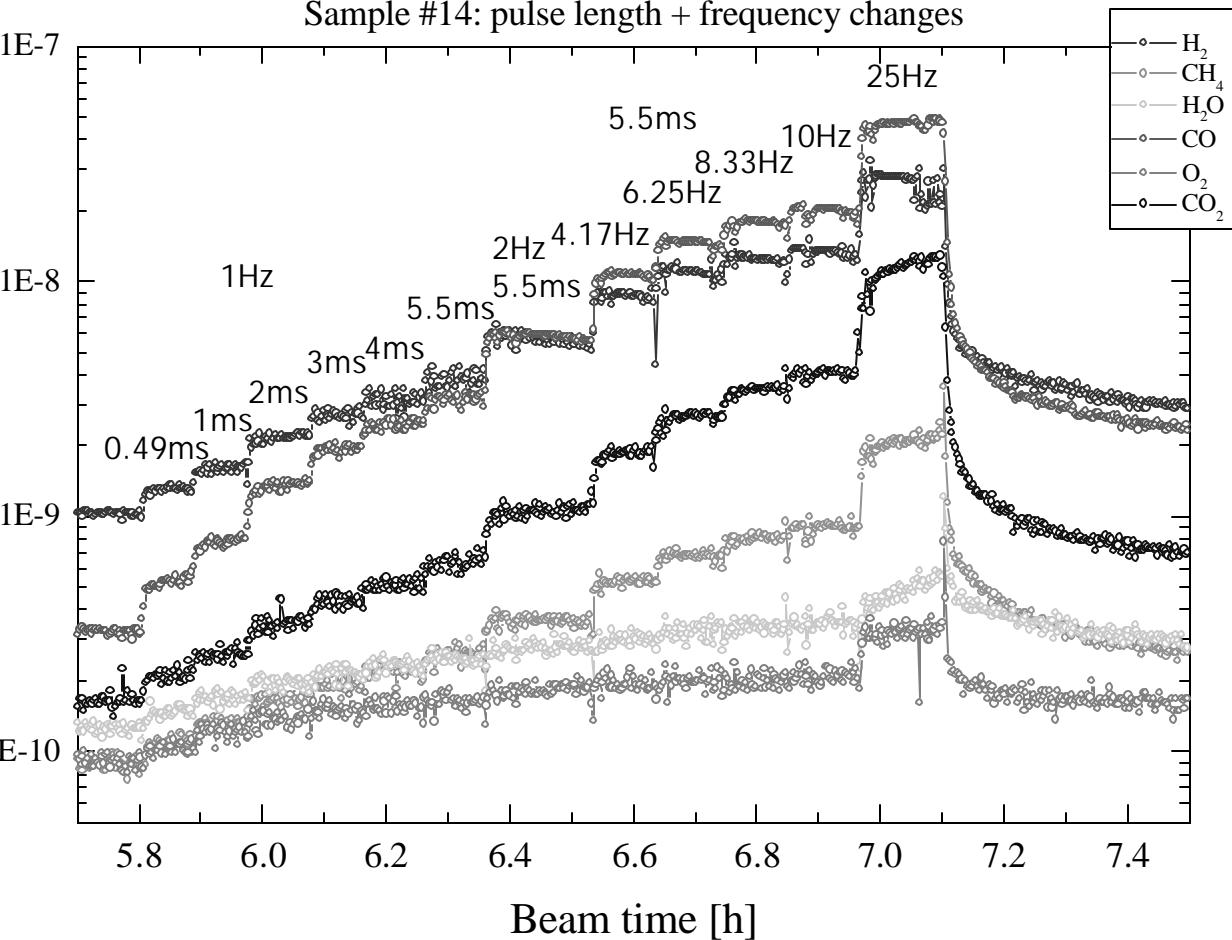


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1.4 MeV/u $Zn^{10+} \Rightarrow 316LN$ (fired)

Flux vs Δp

Sample #14: pulse length + frequency changes



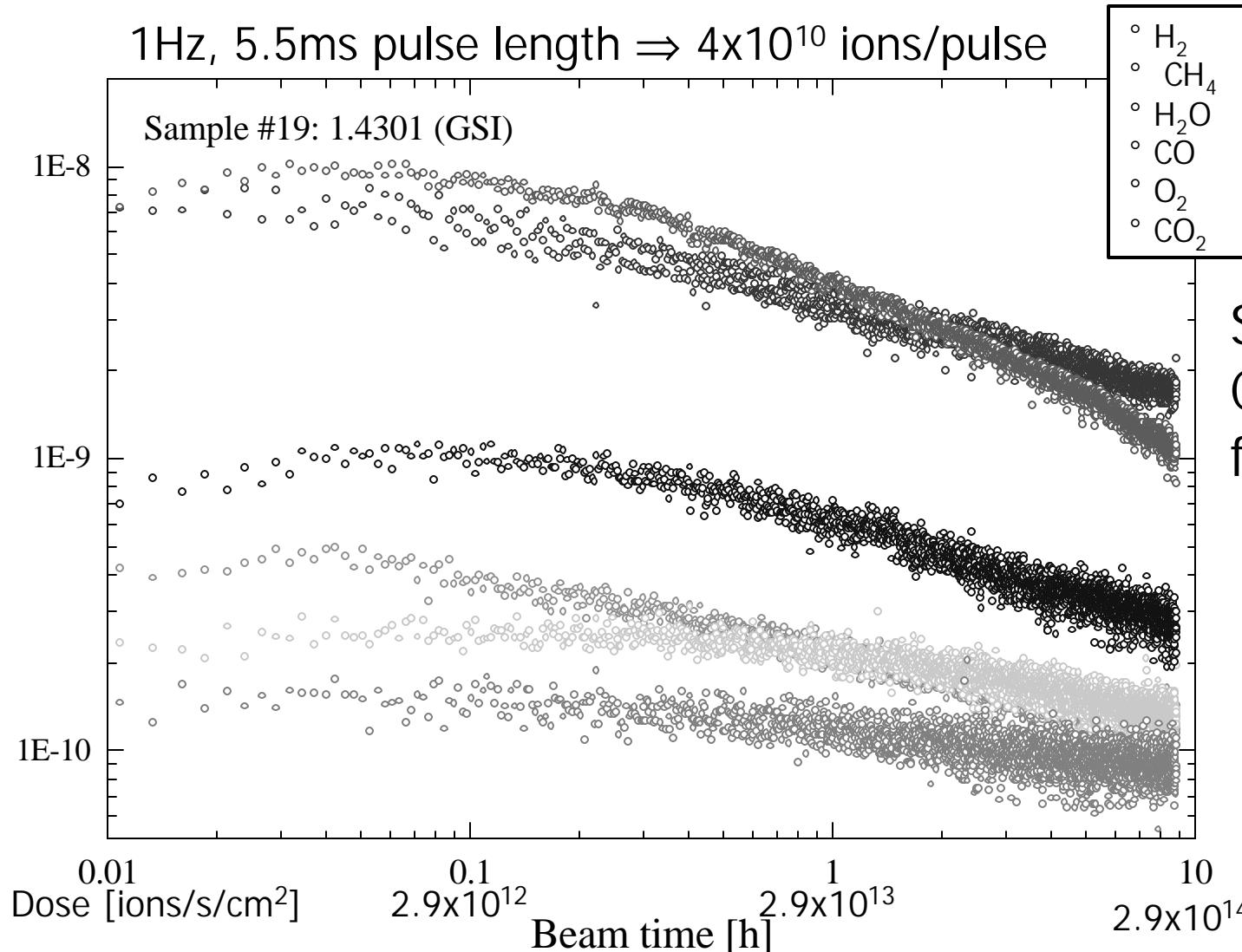
ts by E. Mahner (CERN)



Beam Scrubbing 1.4 MeV/u Zn¹⁰⁺ \Rightarrow 304

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1Hz, 5.5ms pulse length $\Rightarrow 4 \times 10^{10}$ ions/pulse



Plot by E. Mahner (CERN)

Summary & Outlook

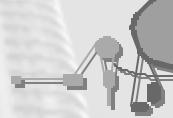
ICFA Workshop, December 9-12, 2008

- ◆ First experiments under perpendicular incidence with different projectile ions and target materials/coatings at 1.4MeV/u at GSI
- ◆ Next Step: Modified(?) experimental setup at UNILAC with energies up to 11MeV/u [implementation of an electron detector]
- ◆ Together with material science: ERDA measurements for surface and bulk analysis up to 1 μ m depth (Ph.D. thesis)

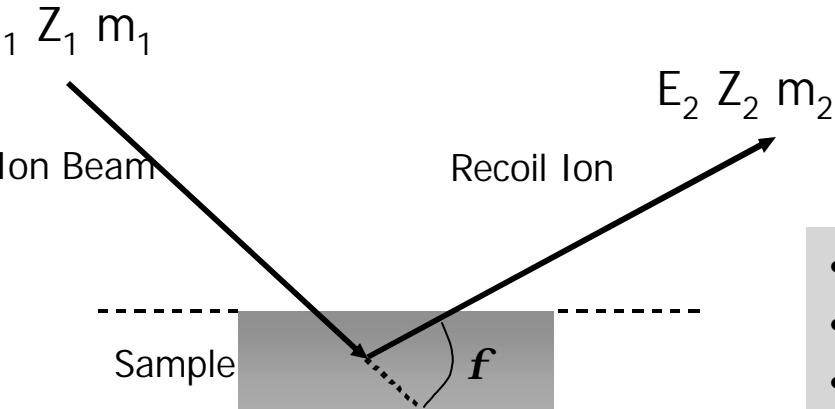
Further to be studied:

- ◆ Desorption at higher energies up to 1GeV/u
- ◆ Desorption of cold vacuum chamber walls for SIS100 and SIS300

Elastic Recoil Ion Detection Analysis (ERDA)



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- same sensitivity for all elements
- Z_1^4 dependence ($m=2Z$)
- depth profile easy accessible

Rutherford-Scattering:

$$\frac{E_2}{m_2} = \frac{4 \cos^2 \mathbf{f}}{(1 + m_2/m_1)^2} \frac{E_1}{m_1}$$

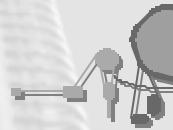
for heavy ions: $m_2/m_1 \ll 1$

→ all recoil ions have approx the same velocity v (→ similar energy loss)

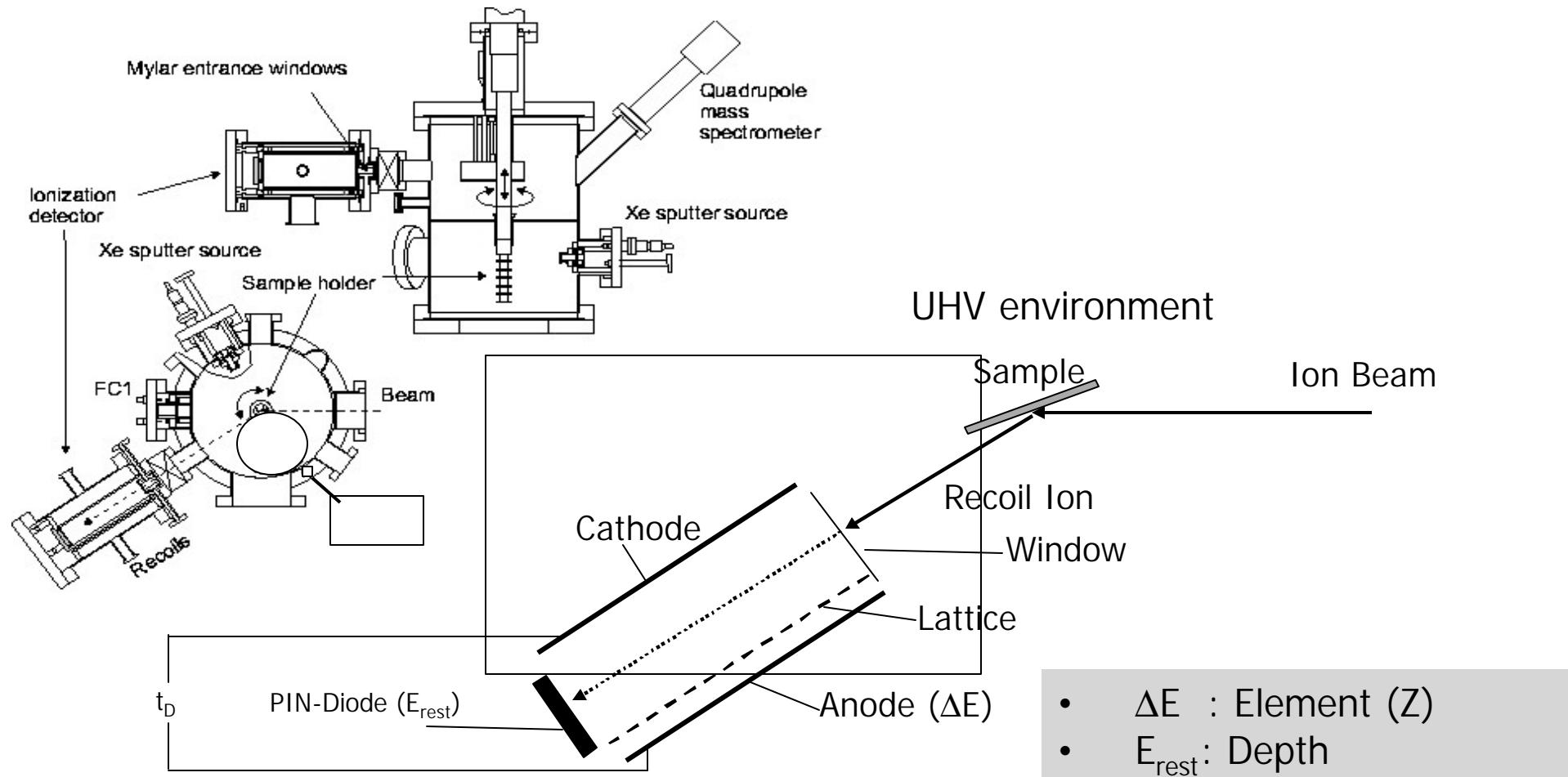
ERDA-Cross Section:

$$s_{ERD} = \left(\frac{Z_1 Z_2 e^2}{2 E_1} \right)^2 \left(\frac{m_1 + m_2}{m_2} \right)^2 \cos^{-3} \mathbf{f}$$

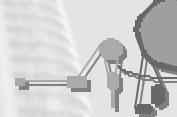
Experimental Setup for ERDA Measurement



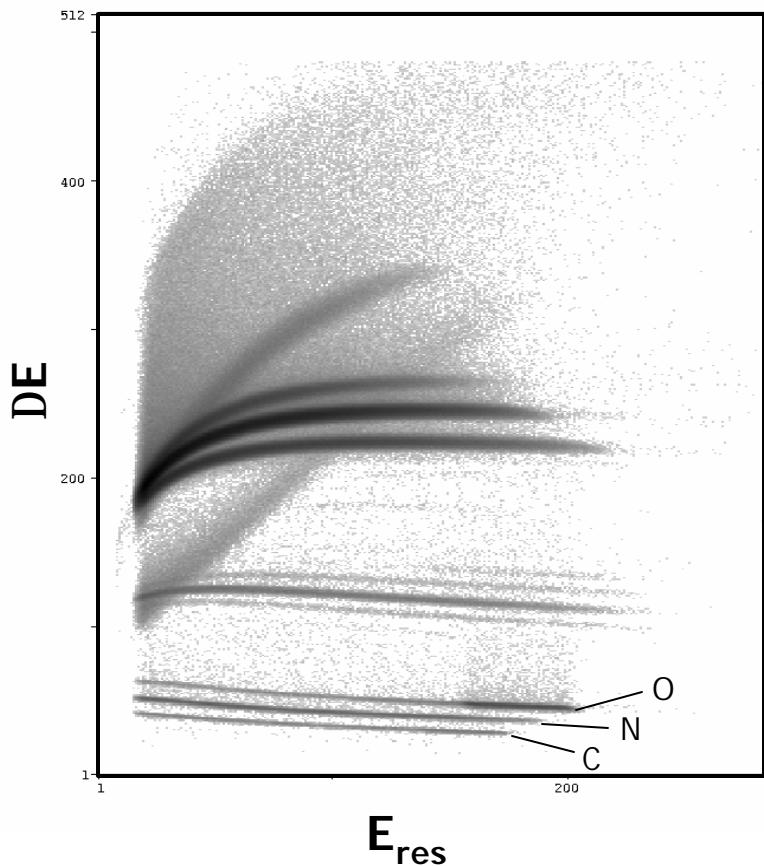
ICFA Workshop, December 9-12, 2008



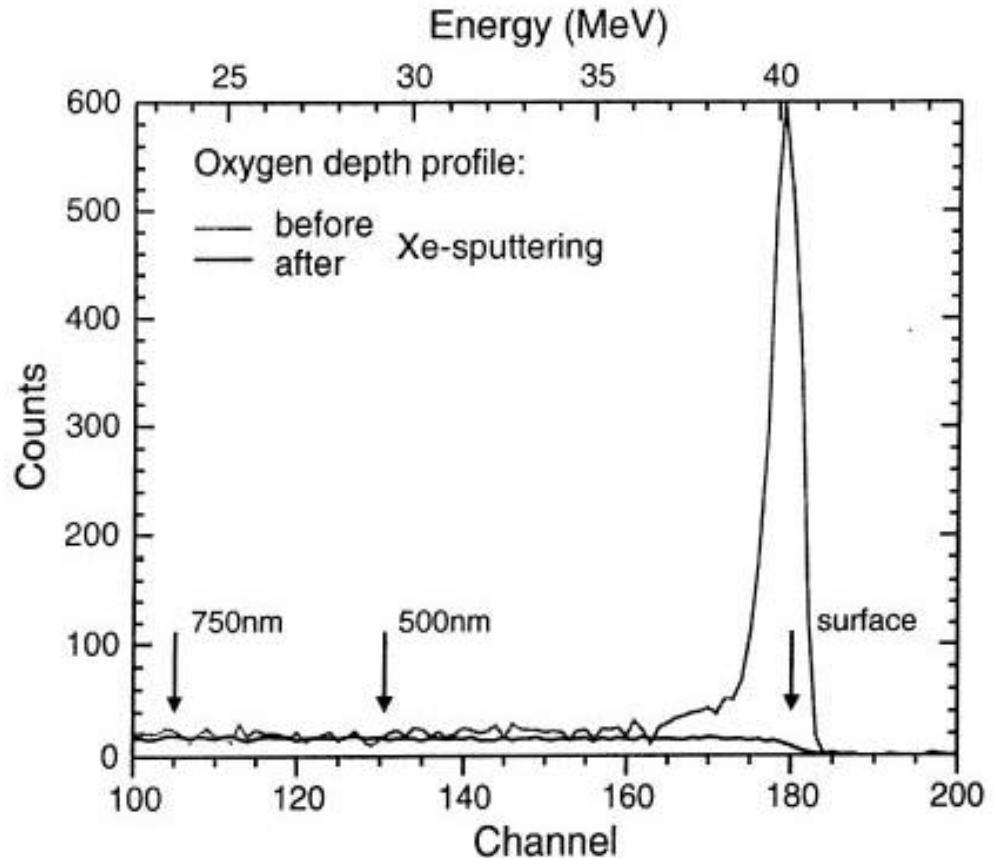
D. Mieskes et al., Measuring sputtering yields of high energy heavy ions on metals, NIM B 146 (1998)



200 MeV Au^{<30+>} → 304 L stainless steel

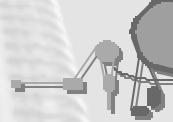


in-situ ERD energy profile of
O-contamination in a Ti - sample



H. D. Mieskes et al., NIM B 146 (1998)

Advantages of ERDA



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- element specific depth profile,
typical depth up to 1 μm with 20 nm resolution
- clear distinction between surface and bulk
- in-situ measurement of material changes under radiation

- combinable with total and partial pressure measurements
- combinable with measurement of electronic desorption yields

Acknowledgement

ICFA Workshop, December 9-12, 2008

- ◆ M. Bender, O. Boine-Frankenheim, B. Franczak, W. Kaufmann, H. Kollmus,
E. Mustafin, H. Reeg, H. Reich-Sprenger, P. Schütt, P. Spiller, U. Weinrich
(GSI; Accelerator Division)
- ◆ E. Mahner (CERN; AT-Division, Vacuum Group)
- ◆ C. Trautmann (GSI; Material Science)
- ◆ W. Assmann (LMU Munich)